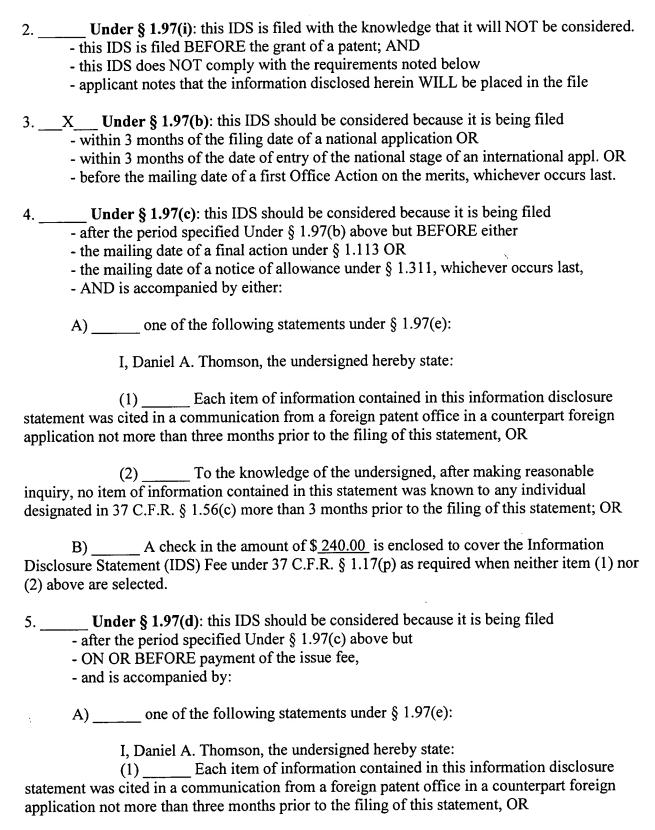


GAU2874

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE .

IN RE APPLICATION OF	: Gerald T. Mearini and Laszlo Takacs	
FOR	: OPTICAL FILTER CONSTRUCTION ATOMIC LAYER CONTROL FOR GENERATION DENSE WAVELEN DIVISION MULTIPLEXER	NEXT
SERIAL NO.	: 09/865,152	T.Car
FILED	: May 24, 2001	RECEIVED OCT 18 2001
LAST OFFICE ACTION	: Unknown	הרהיז רבייובו 1001 8 2001 1001 8 2001
EXAMINER	: Unknown	/ED 2001
GROUP ART UNIT	: 2874	i di di
ATTORNEY DOCKET NO.	: 0937.0013 Akron, OH 44308-1136 October 12, 2001	
**************************************	**************************************	*****
I hereby certify that this INFORMATION §1.56 and §1.97 is being deposited with the envelope addressed to: Commissioner of P this, 2001. **********************************	e United States Postal Service as first cla	ass mail in an
INFORMATION DISCLOSURE ST	ATEMENT UNDER 37 C.F.R. §1.56	and §1.97
Statement (IDS) under at least one of the fo	the applicant files this Information Discollowing five circumstances:	·



(2) To the knowledge of the undersigned, after making reasonable inquiry, no item of information contained in this statement was known to any individual designated in 37 C.F.R. § 1.56(c) more than 3 months prior to the filing of this statement; AND		
B) a petition requesting consideration of the IDS; AND		
C) A check in the amount of \$130.00 is enclosed for the petition fee as set forth under 37 C.F.R. § 1.17(i).		

In accordance with § 1.56 and § 1.97 the references listed below and on the attached form PTO-1449 are being brought to the attention of the Examiner for consideration in connection with the examination of the above-identified patent application. Copies of these cited documents are enclosed.

English-Language Documents

Patentee	Patent No.	Issue Date
Pan, et al	5,748,350	May 5, 1998
Cao	6,205,270	Mar. 20, 2001
Debley et al.	5,529,671	Jun. 25, 1996
Malshe, et al.	5,725,413	Mar. 10, 1998
Sharp	4,747,922	May 31, 1988
Mesh, et al.	6,233,261	May 15, 2001

Foreign Patent Documents in English

Country

Patent No.

Issue Date

Foreign-Language Documents

Country

Patent No.

Issue Date

Other Documents

Kumar, et al.; Near-Infrared Bandpass Filter from Si/SiO2; Multilayer Coatings; February 1999

Suntola, T.; Cost-Effective Processing by Atomic Layer Epitaxy; 1993.

Bachman, et al.; Molecular Layer Expitaxy by Real-Time Optical Process Monitoring; 1997.

H., Kawai, T. Tabata; Atomic Layer Control of the Growth of Oxide Superconductors Using Laser Molecular Beam Epitaxy; 1993

Imai, F., Kunimori, K., and Nozoye, H; Novel Epitaxial Growth Mechanism of Magnesium Oxide/Titanium Oxide Ceramics Superlattice Thin Films Observed by Reflection High-Energy Electron Diffraction; November 8, 1993.

Kildemo, et al.; Real Time Control of the Growth of Silicon Alloy Mulitlayers by Multiwavelength Ellipsometry; 1996.

Spiller, E: Smoothing of Multilayer X-Ray Mirrors by Ion Polishing; March 30, 1989.

Puik, E.J, van der Wiel and Zeijlemaker, H, and Verhoeven, J.; Ion Etching of Thin W Layers: Enhancing Reflectivity of W-C Multilayer Coatings; 1991.

Nishizawa, J., Abe, H., and Kurabayshi, T.J. Electrochem. Soc. 132(5) (1985).

Puik, E.J., et al.; Appln. Surf. Sci. 47 (1991) 251.

Kloidt, A, et al.; Thin Sol Films, 228 (1993) 154.

X Please charge deposit account No. 05-0875 if any additional fees are required.

It is respectfully requested that the Examiner indicate consideration of the cited references by returning a copy of the attached form PTO-1449 with initials or other appropriate marks.

Respectfully submitted,

October 12, 2002

Daniel A. Thomson, Esq.

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